

Search Notes



Application/Control No.

10/530,445

Examiner

Hanh Phan

Applicant(s)/Patent under Reexamination

LEE ET AL.

Art Unit

2613

SEARCHED

Class	Subclass	Date	Examiner
398	33	12/20/07	HP
	7,34		
	79,82		
	140,141		
	25,26		
	27,70		
	71,72		
	91,93,95		
	94,100		
	156,162		
	136,192		
	195,197		
	196		
372	32,34	12/20/07	HP
	35,36,38.02		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
East heard see attached print out in the file	12/20/07	HP
see search JP search		